Application/Control No. Applicant(s)/Patent Under Reexamination YEN ET AL. Examiner Sheela C Chawan Applicant(s)/Patent Under Reexamination YEN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,120,940	06-1992	Willsie, Todd D.	235/462.08
	В	US-5,523,552	06-1996	Shellhammer et al.	235/462.09
	С	US-5,550,365	08-1996	Klancnik et al.	235/462.25
	D	US-5,682,030	10-1997	Kubon, Daniel George	235/462.25
	Ε	US-5,835,615	11-1998	Lubow et al.	382/112
	F	US-4,822,986	04-1989	Guthmueller et al.	235/462.02
	G	US-6,470,096	10-2002	Davies et al.	382/203
	Ι	US-6,193,158	02-2001	Hecht et al.	235/462.16
	٦	US-5,880,451	03-1999	Smith et al.	235/462.1
	J	US-4,901,073	02-1990	Kibrick, Robert I.	341/13
	ĸ	US-6,212,504 B1	04-2001	Hayosh, Thomas David	705/64
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0		4			
	Ρ					
×	σ			,		
	R					
	S					
	۲					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	w	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.